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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC G4
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.7GHz
Co-Processors/DSP	Multimedia; SIMD
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	360-BCBGA, FCCBGA
Supplier Device Package	360-FCCBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmc7448hx1700lc

- Four vector units and 32-entry vector register file (VRs)
 - Vector permute unit (VPU)
 - Vector integer unit 1 (VIU1) handles short-latency AltiVec™ integer instructions, such as vector add instructions (for example, **vaddsbs**, **vaddshs**, and **vaddsws**).
 - Vector integer unit 2 (VIU2) handles longer-latency AltiVec integer instructions, such as vector multiply add instructions (for example, **vmhaddshs**, **vmhraddshs**, and **vmladduhm**).
 - Vector floating-point unit (VFPU)
- Three-stage load/store unit (LSU)
 - Supports integer, floating-point, and vector instruction load/store traffic
 - Four-entry vector touch queue (VTQ) supports all four architected AltiVec data stream operations
 - Three-cycle GPR and AltiVec load latency (byte, half word, word, vector) with one-cycle throughput
 - Four-cycle FPR load latency (single, double) with one-cycle throughput
 - No additional delay for misaligned access within double-word boundary
 - A dedicated adder calculates effective addresses (EAs).
 - Supports store gathering
 - Performs alignment, normalization, and precision conversion for floating-point data
 - Executes cache control and TLB instructions
 - Performs alignment, zero padding, and sign extension for integer data
 - Supports hits under misses (multiple outstanding misses)
 - Supports both big- and little-endian modes, including misaligned little-endian accesses
- Three issue queues, FIQ, VIQ, and GIQ, can accept as many as one, two, and three instructions, respectively, in a cycle. Instruction dispatch requires the following:
 - Instructions can only be dispatched from the three lowest IQ entries—IQ0, IQ1, and IQ2.
 - A maximum of three instructions can be dispatched to the issue queues per clock cycle.
 - Space must be available in the CQ for an instruction to dispatch (this includes instructions that are assigned a space in the CQ but not in an issue queue).
- Rename buffers
 - 16 GPR rename buffers
 - 16 FPR rename buffers
 - 16 VR rename buffers
- Dispatch unit
 - Decode/dispatch stage fully decodes each instruction
- Completion unit
 - Retires an instruction from the 16-entry completion queue (CQ) when all instructions ahead of it have been completed, the instruction has finished executing, and no exceptions are pending
 - Guarantees sequential programming model (precise exception model)

- Reliability and serviceability
 - Parity checking on system bus
 - Parity checking on the L1 caches and L2 data tags
 - ECC or parity checking on L2 data

3 Comparison with the MPC7447A, MPC7447, MPC7445, and MPC7441

Table 1 compares the key features of the MPC7448 with the key features of the earlier MPC7447A, MPC7447, MPC7445, and MPC7441. All are based on the MPC7450 RISC microprocessor and are architecturally very similar. The MPC7448 is identical to the MPC7447A, but the MPC7448 supports 1 Mbyte of L2 cache with ECC and the use of dynamic frequency switching (DFS) with more bus-to-core ratios.

Table 1. Microarchitecture Comparison

Microarchitectural Specs	MPC7448	MPC7447A	MPC7447	MPC7445	MPC7441
Basic Pipeline Functions					
Logic inversions per cycle			18		
Pipeline stages up to execute			5		
Total pipeline stages (minimum)			7		
Pipeline maximum instruction throughput			3 + branch		
Pipeline Resources					
Instruction buffer size			12		
Completion buffer size			16		
Renames (integer, float, vector)			16, 16, 16		
Maximum Execution Throughput					
SFX			3		
Vector			2 (any 2 of 4 units)		
Scalar floating-point			1		
Out-of-Order Window Size in Execution Queues					
SFX integer units			1 entry × 3 queues		
Vector units			In order, 4 queues		
Scalar floating-point unit			In order		
Branch Processing Resources					
Prediction structures			BTIC, BHT, link stack		
BTIC size, associativity			128-entry, 4-way		
BHT size			2K-entry		
Link stack depth			8		
Unresolved branches supported			3		
Branch taken penalty (BTIC hit)			1		
Minimum misprediction penalty			6		

Table 1. Microarchitecture Comparison (continued)

Microarchitectural Specs	MPC7448	MPC7447A	MPC7447	MPC7445	MPC7441
Execution Unit Timings (Latency-Throughput)					
Aligned load (integer, float, vector)	3-1, 4-1, 3-1				
Misaligned load (integer, float, vector)	4-2, 5-2, 4-2				
L1 miss, L2 hit latency with ECC (data/instruction)	12/16	—			
L1 miss, L2 hit latency without ECC (data/instruction)	11/15	9/13			
SFX (add, sub, shift, rot, cmp, logicals)	1-1				
Integer multiply (32 × 8, 32 × 16, 32 × 32)	4-1, 4-1, 5-2				
Scalar float	5-1				
VSFX (vector simple)	1-1				
VCFX (vector complex)	4-1				
VFPU (vector float)	4-1				
VPER (vector permute)	2-1				
MMUs					
TLBs (instruction and data)	128-entry, 2-way				
Tablewalk mechanism	Hardware + software				
Instruction BATs/data BATs	8/8	8/8	8/8	8/8	4/4
L1 I Cache/D Cache Features					
Size	32K/32K				
Associativity	8-way				
Locking granularity	Way				
Parity on I cache	Word				
Parity on D cache	Byte				
Number of D cache misses (load/store)	5/2	5/1			
Data stream touch engines	4 streams				
On-Chip Cache Features					
Cache level	L2				
Size/associativity	1-Mbyte/ 8-way	512-Kbyte/8-way	256-Kbyte/8-way		
Access width	256 bits				
Number of 32-byte sectors/line	2	2			
Parity tag	Byte	Byte			
Parity data	Byte	Byte			
Data ECC	64-bit	—			
Thermal Control					
Dynamic frequency switching divide-by-two mode	Yes	Yes	No	No	No
Dynamic frequency switching divide-by-four mode	Yes	No	No	No	No
Thermal diode	Yes	Yes	No	No	No

Table 5 provides the package thermal characteristics for the MPC7448. For more information regarding thermal management, see Section 9.7, “Power and Thermal Management Information.”

Table 5. Package Thermal Characteristics¹

Characteristic	Symbol	Value	Unit	Notes
Junction-to-ambient thermal resistance, natural convection, single-layer (1s) board	$R_{\theta JA}$	26	•C/W	2, 3
Junction-to-ambient thermal resistance, natural convection, four-layer (2s2p) board	$R_{\theta JMA}$	19	•C/W	2, 4
Junction-to-ambient thermal resistance, 200 ft/min airflow, single-layer (1s) board	$R_{\theta JMA}$	22	•C/W	2, 4
Junction-to-ambient thermal resistance, 200 ft/min airflow, four-layer (2s2p) board	$R_{\theta JMA}$	16	•C/W	2, 4
Junction-to-board thermal resistance	$R_{\theta JB}$	11	•C/W	5
Junction-to-case thermal resistance	$R_{\theta JC}$	< 0.1	•C/W	6

Notes:

1. Refer to Section 9.7, “Power and Thermal Management Information,” for details about thermal management.
2. Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.
3. Per JEDEC JESD51-2 with the single-layer board horizontal
4. Per JEDEC JESD51-6 with the board horizontal
5. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
6. This is the thermal resistance between die and case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the calculated case temperature. The actual value of $R_{\theta JC}$ for the part is less than 0.1°C/W.

Table 6 provides the DC electrical characteristics for the MPC7448.

Table 6. DC Electrical Specifications

At recommended operating conditions. See Table 4.

Characteristic	Nominal Bus Voltage ¹	Symbol	Min	Max	Unit	Notes
Input high voltage (all inputs)	1.5	V_{IH}	$OV_{DD} \times 0.65$	$OV_{DD} + 0.3$	V	2
	1.8		$OV_{DD} \times 0.65$	$OV_{DD} + 0.3$		
	2.5		1.7	$OV_{DD} + 0.3$		
Input low voltage (all inputs)	1.5	V_{IL}	-0.3	$OV_{DD} \times 0.35$	V	2
	1.8		-0.3	$OV_{DD} \times 0.35$		
	2.5		-0.3	0.7		
Input leakage current, all signals except BVSELO, LSSD_MODE, TCK, TDI, TMS, TRST: $V_{in} = OV_{DD}$ $V_{in} = GND$	—	I_{in}	—	50 -50	μA	2, 3
Input leakage current, BVSELO, LSSD_MODE, TCK, TDI, TMS, TRST: $V_{in} = OV_{DD}$ $V_{in} = GND$	—	I_{in}	—	50 -2000	μA	2, 6

when running a typical benchmark at temperatures in a typical system. The Full-Power Mode–Thermal value is intended to represent the sustained power consumption of the device when running a typical code sequence at high temperature and is recommended to be used as the basis for designing a thermal solution; see [Section 9.7, “Power and Thermal Management Information”](#) for more information on thermal solutions. The Full-Power Mode–Maximum value is recommended to be used for power supply design because this represents the maximum peak power draw of the device that a power supply must be capable of sourcing without voltage droop. For information on power consumption when dynamic frequency switching is enabled, see [Section 9.7.5, “Dynamic Frequency Switching \(DFS\)”](#).

Table 7. Power Consumption for MPC7448 at Maximum Rated Frequency

	Die Junction Temperature (T _j)	Maximum Processor Core Frequency (Speed Grade, MHz)				Unit	Notes
		1000 MHz	1420 MHz	1600 MHz	1700 MHz		
Full-Power Mode							
Typical	65 °C	15.0	19.0	20.0	21.0	W	1, 2
Thermal	105 °C	18.6	23.3	24.4	25.6	W	1, 5
Maximum	105 °C	21.6	27.1	28.4	29.8	W	1, 3
Nap Mode							
Typical	105 °C	11.1	11.8	13.0	13.0	W	1, 6
Sleep Mode							
Typical	105 °C	10.8	11.4	12.5	12.5	W	1, 6
Deep Sleep Mode (PLL Disabled)							
Typical	105 °C	10.4	11.0	12.0	12.0	W	1, 6

Notes:

1. These values specify the power consumption for the core power supply (V_{DD}) at nominal voltage and apply to all valid processor bus frequencies and configurations. The values do not include I/O supply power (OV_{DD}) or PLL supply power (AV_{DD}). OV_{DD} power is system dependent but is typically < 5% of V_{DD} power. Worst case power consumption for AV_{DD} < 13 mW. Freescale also offers MPC7448 part numbers that meet lower power consumption specifications; for more information on these devices, see [Section 11.2, “Part Numbers Not Fully Addressed by This Document.”](#)
2. Typical power consumption is an average value measured with the processor operating at its rated maximum processor core frequency (except for Deep Sleep Mode), at nominal recommended V_{DD} (see [Table 4](#)) and 65°C while running the Dhrystone 2.1 benchmark and achieving 2.3 Dhrystone MIPs/MHz. This parameter is not 100% tested but periodically sampled.
3. Maximum power consumption is the average measured with the processor operating at its rated maximum processor core frequency, at nominal V_{DD} and maximum operating junction temperature (see [Table 4](#)) while running an entirely cache-resident, contrived sequence of instructions to keep all the execution units maximally busy.
4. Doze mode is not a user-definable state; it is an intermediate state between full-power and either nap or sleep mode. As a result, power consumption for this mode is not tested.
5. Thermal power consumption is an average value measured at the nominal recommended V_{DD} (see [Table 4](#)) and 105 °C while running the Dhrystone 2.1 benchmark and achieving 2.3 Dhrystone MIPs/MHz. This parameter is not 100% tested but periodically sampled.
6. Typical power consumption for these modes is measured at the nominal recommended V_{DD} (see [Table 4](#)) and 105 °C in the mode described. This parameter is not 100% tested but is periodically sampled.

Figure 3 provides the SYSCLK input timing diagram.

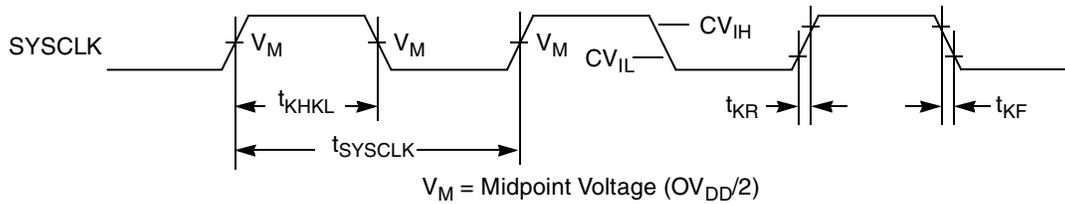


Figure 3. SYSCLK Input Timing Diagram

5.2.2 Processor Bus AC Specifications

Table 9 provides the processor bus AC timing specifications for the MPC7448 as defined in Figure 4 and Figure 5.

Table 9. Processor Bus AC Timing Specifications¹

At recommended operating conditions. See Table 4.

Parameter	Symbol ²	All Speed Grades		Unit	Notes
		Min	Max		
Input setup times: A[0:35], AP[0:4] D[0:63], DP[0:7] \overline{AACK} , \overline{ARTRY} , \overline{BG} , $\overline{CKSTP_IN}$, \overline{DBG} , DTI[0:3], \overline{GBL} , TT[0:4], \overline{QACK} , \overline{TA} , \overline{TBEN} , \overline{TEA} , \overline{TS} , EXT_QUAL, $\overline{PMON_IN}$, \overline{SHD} [0:1] BMODE[0:1], BVSEL[0:1]	t_{AVKH} t_{DVKH} t_{IVKH} t_{MVKH}	1.5 1.5 1.5 1.5	— — — —	ns	— — — 8
Input hold times: A[0:35], AP[0:4] D[0:63], DP[0:7] \overline{AACK} , \overline{ARTRY} , \overline{BG} , $\overline{CKSTP_IN}$, \overline{DBG} , DTI[0:3], \overline{GBL} , TT[0:4], \overline{QACK} , \overline{TA} , \overline{TBEN} , \overline{TEA} , \overline{TS} , EXT_QUAL, $\overline{PMON_IN}$, \overline{SHD} [0:1] BMODE[0:1], BVSEL[0:1]	t_{AXKH} t_{DXKH} t_{IXKH} t_{MXKH}	0 0 0 0	— — — —	ns	— — — 8
Output valid times: A[0:35], AP[0:4] D[0:63], DP[0:7] \overline{BR} , \overline{CI} , \overline{DRDY} , \overline{GBL} , \overline{HIT} , $\overline{PMON_OUT}$, \overline{QREQ} , \overline{TBST} , \overline{TSIZ} [0:2], TT[0:4], \overline{WT} \overline{TS} \overline{ARTRY} , \overline{SHD} [0:1]	t_{KHAV} t_{KHVD} t_{KHOV} t_{KHTSV} t_{KHARV}	— — — — —	1.8 1.8 1.8 1.8 1.8	ns	
Output hold times: A[0:35], AP[0:4] D[0:63], DP[0:7] \overline{BR} , \overline{CI} , \overline{DRDY} , \overline{GBL} , \overline{HIT} , $\overline{PMON_OUT}$, \overline{QREQ} , \overline{TBST} , \overline{TSIZ} [0:2], TT[0:4], \overline{WT} \overline{TS} \overline{ARTRY} , \overline{SHD} [0:1]	t_{KHAX} t_{KHDX} t_{KHOX} t_{KHTSX} t_{KHARX}	0.5 0.5 0.5 0.5 0.5	— — — — —	ns	
SYSCLK to output enable	t_{KHOE}	0.5	—	ns	5

5.2.3 IEEE Std. 1149.1 AC Timing Specifications

Table 10 provides the IEEE Std. 1149.1 (JTAG) AC timing specifications as defined in Figure 8 through Figure 11.

Table 10. JTAG AC Timing Specifications (Independent of SYSCLK)¹

At recommended operating conditions. See Table 4.

Parameter	Symbol	Min	Max	Unit	Notes
TCK frequency of operation	f_{TCLK}	0	33.3	MHz	
TCK cycle time	t_{TCLK}	30	—	ns	
TCK clock pulse width measured at 1.4 V	t_{HJL}	15	—	ns	
TCK rise and fall times	t_{JR} and t_{JF}	—	2	ns	
\overline{TRST} assert time	t_{TRST}	25	—	ns	2
Input setup times: Boundary-scan data TMS, TDI	t_{DVJH} t_{IVJH}	4 0	— —	ns	3
Input hold times: Boundary-scan data TMS, TDI	t_{DXJH} t_{IXJH}	20 25	— —	ns	3
Valid times: Boundary-scan data TDO	t_{JLDV} t_{JLOV}	4 4	20 25	ns	4
Output hold times: Boundary-scan data TDO	t_{JLDX} t_{JLOX}	30 30	— —	ns	4
TCK to output high impedance: Boundary-scan data TDO	t_{JLDZ} t_{JLOZ}	3 3	19 9	ns	4, 5

Notes:

- All outputs are measured from the midpoint voltage of the falling/rising edge of TCLK to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load (see Figure 7). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
- \overline{TRST} is an asynchronous level sensitive signal. The time is for test purposes only.
- Non-JTAG signal input timing with respect to TCK.
- Non-JTAG signal output timing with respect to TCK.
- Guaranteed by design and characterization.

Figure 7 provides the AC test load for TDO and the boundary-scan outputs of the MPC7448.

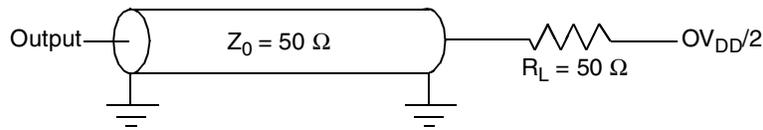


Figure 7. Alternate AC Test Load for the JTAG Interface

Figure 8 provides the JTAG clock input timing diagram.

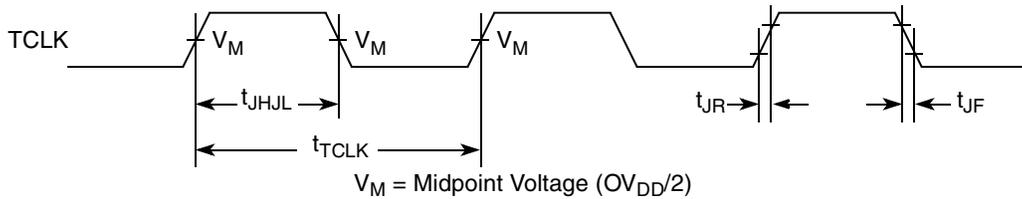


Figure 8. JTAG Clock Input Timing Diagram

Figure 9 provides the $\overline{\text{TRST}}$ timing diagram.

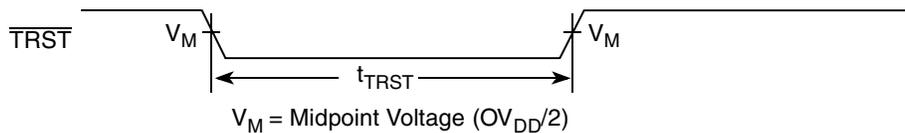


Figure 9. $\overline{\text{TRST}}$ Timing Diagram

Figure 10 provides the boundary-scan timing diagram.

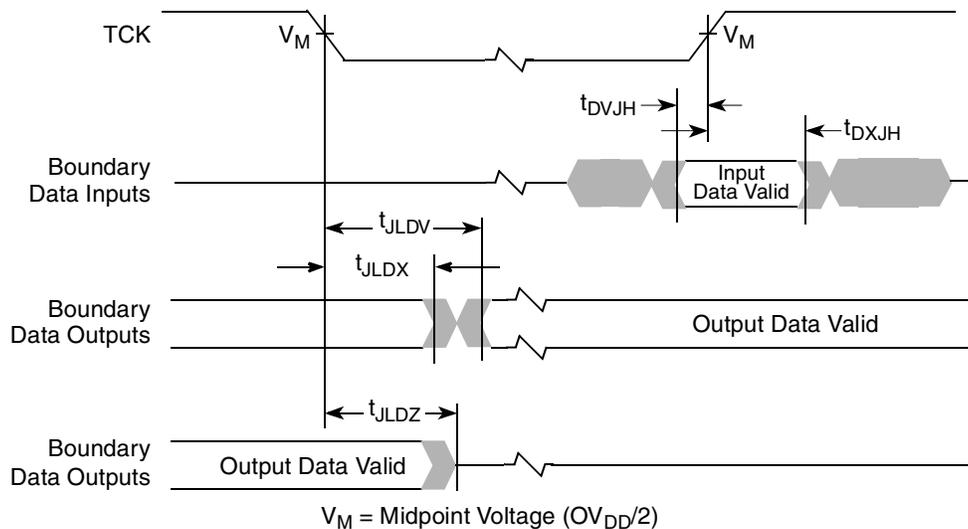


Figure 10. Boundary-Scan Timing Diagram

Figure 11 provides the test access port timing diagram.

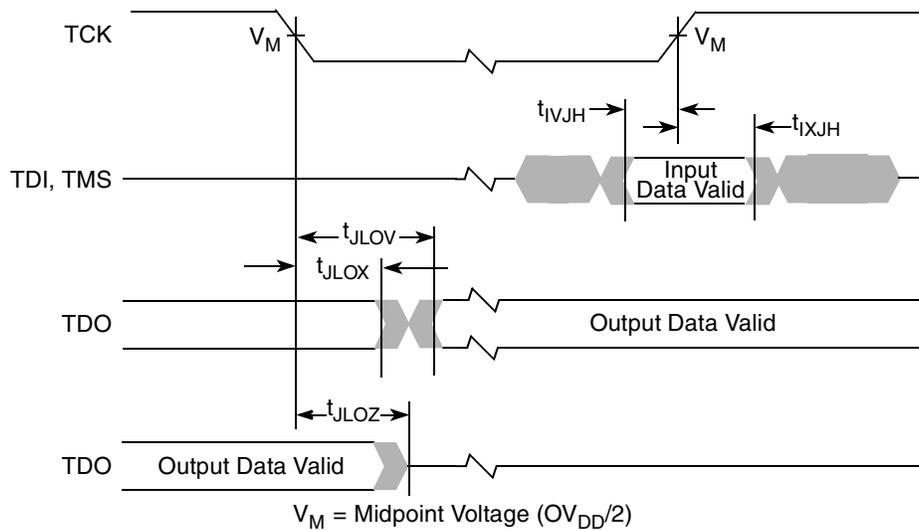


Figure 11. Test Access Port Timing Diagram

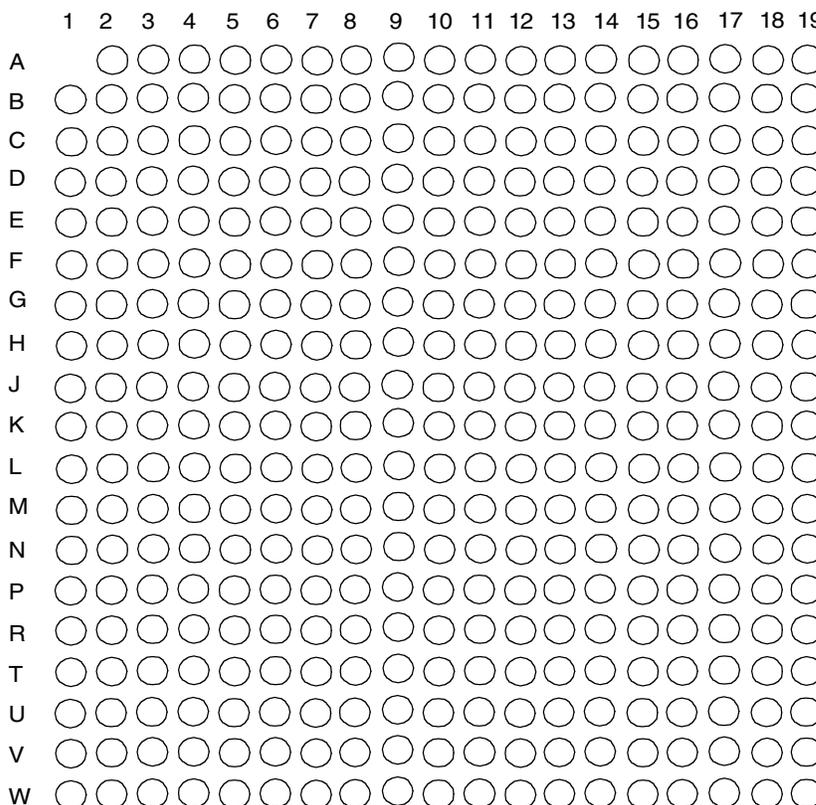
5.3 Voltage and Frequency Derating

Voltage and frequency derating is no longer supported for part numbers described by this document beginning with datecode 0613. (See [Section 11, “Part Numbering and Marking,”](#) for information on date code markings.) It is supported by some MPC7448 part numbers which target low-power applications; see [Section 11.2, “Part Numbers Not Fully Addressed by This Document”](#) and the referenced MPC7448 Hardware Specification Addenda for more information on these low-power devices. For those devices which previously supported this feature, information has been archived in the *Chip Errata for the MPC7448* (document order no. MPC7448CE).

6 Pin Assignments

Figure 12 (in Part A) shows the pinout of the MPC7448, 360 high coefficient of thermal expansion ceramic ball grid array (HCTE) package as viewed from the top surface. Part B shows the side profile of the HCTE package to indicate the direction of the top surface view.

Part A



Not to Scale

Part B

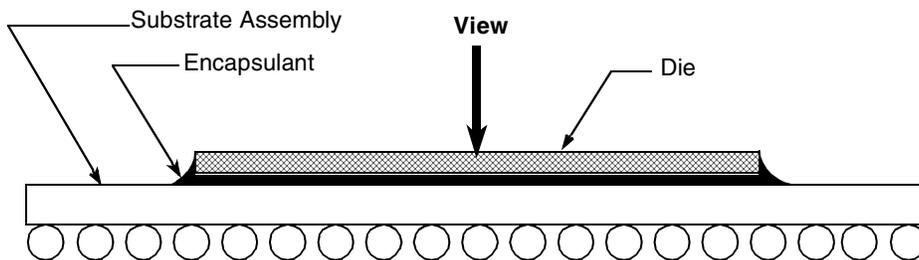


Figure 12. Pinout of the MPC7448, 360 HCTE Package as Viewed from the Top Surface

Table 11. Pinout Listing for the MPC7448, 360 HCTE Package (continued)

Signal Name	Pin Number	Active	I/O	Notes
$\overline{\text{LVRAM}}$	B10	—	—	12, 20, 22
NC (no connect)	A6, A14, A15, B14, B15, C14, C15, C16, C17, C18, C19, D14, D15, D16, D17, D18, D19, E14, E15, F14, F15, G14, G15, H15, H16, J15, J16, J17, J18, J19, K15, K16, K17, K18, K19, L15, L16, L17, L18, L19	—	—	11
$\overline{\text{LSSD_MODE}}$	E8	Low	Input	6, 12
$\overline{\text{MCP}}$	C9	Low	Input	
OV_{DD}	B4, C2, C12, D5, F2, H3, J5, K2, L5, M3, N6, P2, P8, P11, R4, R13, R16, T6, T9, U2, U12, U16, V4, V7, V10, V14	—	—	
OVDD_SENSE	E18, G18	—	—	16
$\text{PLL_CFG}[0:4]$	B8, C8, C7, D7, A7	High	Input	
$\text{PLL_CFG}[5]$	D10	High	Input	9, 20
$\overline{\text{PMON_IN}}$	D9	Low	Input	13
$\overline{\text{PMON_OUT}}$	A9	Low	Output	
$\overline{\text{QACK}}$	G5	Low	Input	
$\overline{\text{QREQ}}$	P4	Low	Output	
$\overline{\text{SHD}}[0:1]$	E4, H5	Low	I/O	3
$\overline{\text{SMI}}$	F9	Low	Input	
$\overline{\text{SRESET}}$	A2	Low	Input	
SYSCLK	A10	—	Input	
$\overline{\text{TA}}$	K6	Low	Input	
TBEN	E1	High	Input	
$\overline{\text{TBST}}$	F11	Low	Output	
TCK	C6	High	Input	
TDI	B9	High	Input	6
TDO	A4	High	Output	
$\overline{\text{TEA}}$	L1	Low	Input	
TEMP_ANODE	N18	—	—	17
TEMP_CATHODE	N19	—	—	17
TMS	F1	High	Input	6
$\overline{\text{TRST}}$	A5	Low	Input	6, 14
$\overline{\text{TS}}$	L4	Low	I/O	3
$\text{TSIZ}[0:2]$	G6, F7, E7	High	Output	
$\text{TT}[0:4]$	E5, E6, F6, E9, C5	High	I/O	
$\overline{\text{WT}}$	D3	Low	Output	
V_{DD}	H8, H10, H12, J7, J9, J11, J13, K8, K10, K12, K14, L7, L9, L11, L13, M8, M10, M12	—	—	
V_{DD}	A13, A16, A18, B17, B19, C13, E13, E16, F12, F17, F19, G11, G16, H14, H17, H19, M14, M16, M18, N15, N17, P16, P18	—	—	15

9.1.2 System Bus Clock (SYSCLK) and Spread Spectrum Sources

Spread spectrum clock sources are an increasingly popular way to control electromagnetic interference emissions (EMI) by spreading the emitted noise to a wider spectrum and reducing the peak noise magnitude in order to meet industry and government requirements. These clock sources intentionally add long-term jitter in order to diffuse the EMI spectral content. The jitter specification given in [Table 8](#) considers short-term (cycle-to-cycle) jitter only and the clock generator's cycle-to-cycle output jitter should meet the MPC7448 input cycle-to-cycle jitter requirement. Frequency modulation and spread are separate concerns, and the MPC7448 is compatible with spread spectrum sources if the recommendations listed in [Table 13](#) are observed.

Table 13. Spread Spectrum Clock Source Recommendations

At recommended operating conditions. See [Table 4](#).

Parameter	Min	Max	Unit	Notes
Frequency modulation	—	50	kHz	1
Frequency spread	—	1.0	%	1, 2

Notes:

1. Guaranteed by design
2. SYSCLK frequencies resulting from frequency spreading, and the resulting core and VCO frequencies, must meet the minimum and maximum specifications given in [Table 8](#).

It is imperative to note that the processor's minimum and maximum SYSCLK, core, and VCO frequencies must not be exceeded regardless of the type of clock source. Therefore, systems in which the processor is operated at its maximum rated core or bus frequency should avoid violating the stated limits by using down-spreading only.

9.2 Power Supply Design and Sequencing

The following sections provide detailed information regarding power supply design for the MPC7448.

9.2.1 Power Supply Sequencing

The MPC7448 requires its power rails and clock to be applied in a specific sequence to ensure proper device operation and to prevent device damage. The power sequencing requirements are as follows:

- AV_{DD} must be delayed with respect to V_{DD} by the RC time constant of the PLL filter circuit described in [Section 9.2.2, "PLL Power Supply Filtering"](#). This time constant is nominally 100 μ s.
- OV_{DD} may ramp anytime before or after V_{DD} and AV_{DD} .

Additionally, the following requirements exist regarding the application of SYSCLK:

- The voltage at the SYSCLK input must not exceed V_{DD} until V_{DD} has ramped to 0.9 V.
- The voltage at the SYSCLK input must not exceed OV_{DD} by more 20% during transients (see overshoot/undershoot specifications in [Figure 2](#)) or 0.3 V DC (see [Table 2](#)) at any time.

9.4 Output Buffer DC Impedance

The MPC7448 processor bus drivers are characterized over process, voltage, and temperature. To measure Z_0 , an external resistor is connected from the chip pad to OV_{DD} or GND. The value of each resistor is varied until the pad voltage is $OV_{DD}/2$. Figure 20 shows the driver impedance measurement.

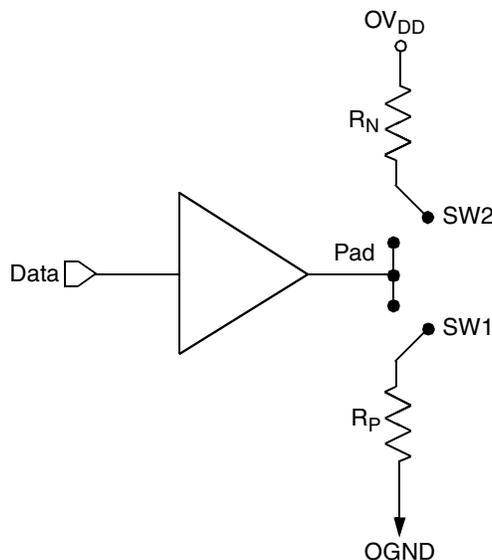


Figure 20. Driver Impedance Measurement

The output impedance is the average of two components—the resistances of the pull-up and pull-down devices. When data is held low, SW2 is closed (SW1 is open), and R_N is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_N then becomes the resistance of the pull-down devices. When data is held high, SW1 is closed (SW2 is open), and R_P is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_P then becomes the resistance of the pull-up devices. R_P and R_N are designed to be close to each other in value. Then, $Z_0 = (R_P + R_N)/2$.

Table 15 summarizes the signal impedance results. The impedance increases with junction temperature and is relatively unaffected by bus voltage.

Table 15. Impedance Characteristics

At recommended operating conditions. See Table 4

Impedance		Processor Bus	Unit
Z_0	Typical	33–42	Ω
	Maximum	31–51	Ω

9.5 Pull-Up/Pull-Down Resistor Requirements

The MPC7448 requires high-resistive (weak: 4.7-K Ω) pull-up resistors on several control pins of the bus interface to maintain the control signals in the negated state after they have been actively negated and released by the MPC7448 or other bus masters. These pins are: \overline{TS} , \overline{ARTRY} , \overline{SHDO} , and \overline{SHDI} .

Some pins designated as being factory test pins must be pulled up to OV_{DD} or down to GND to ensure proper device operation. The pins that must be pulled up to OV_{DD} are $\overline{LSSD_MODE}$ and TEST[0:3]; the pins that must be pulled down to GND are L1_TSTCLK and TEST[4]. The CKSTP_IN signal should

to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in [Figure 21](#) allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well. If the JTAG interface and COP header will not be used, $\overline{\text{TRST}}$ should be tied to $\overline{\text{HRESET}}$ through a 0- Ω isolation resistor so that it is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted, ensuring that the JTAG scan chain is initialized during power-on. Although Freescale recommends that the COP header be designed into the system as shown in [Figure 21](#), if this is not possible, the isolation resistor will allow future access to $\overline{\text{TRST}}$ in the case where a JTAG interface may need to be wired onto the system in debug situations.

The COP header shown in [Figure 21](#) adds many benefits—breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features are possible through this interface—and can be as inexpensive as an unpopulated footprint for a header to be added when needed.

The COP interface has a standard header for connection to the target system, based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

There is no standardized way to number the COP header shown in [Figure 21](#); consequently, many different pin numbers have been observed from emulator vendors. Some are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom, while still others number the pins counter clockwise from pin 1 (as with an IC). Regardless of the numbering, the signal placement recommended in [Figure 21](#) is common to all known emulators.

The $\overline{\text{QACK}}$ signal shown in [Figure 21](#) is usually connected to the bridge chip or other system control logic in a system and is an input to the MPC7448 informing it that it can go into the quiescent state. Under normal operation this occurs during a low-power mode selection. In order for COP to work, the MPC7448 must see this signal asserted (pulled down). While shown on the COP header, not all emulator products drive this signal. If the product does not, a pull-down resistor can be populated to assert this signal. Additionally, some emulator products implement open-drain type outputs and can only drive $\overline{\text{QACK}}$ asserted; for these tools, a pull-up resistor can be implemented to ensure this signal is negated when it is not being driven by the tool. Note that the pull-up and pull-down resistors on the $\overline{\text{QACK}}$ signal are mutually exclusive and it is never necessary to populate both in a system. To preserve correct power-down operation, $\overline{\text{QACK}}$ should be merged through logic so that it also can be driven by the bridge or system logic.

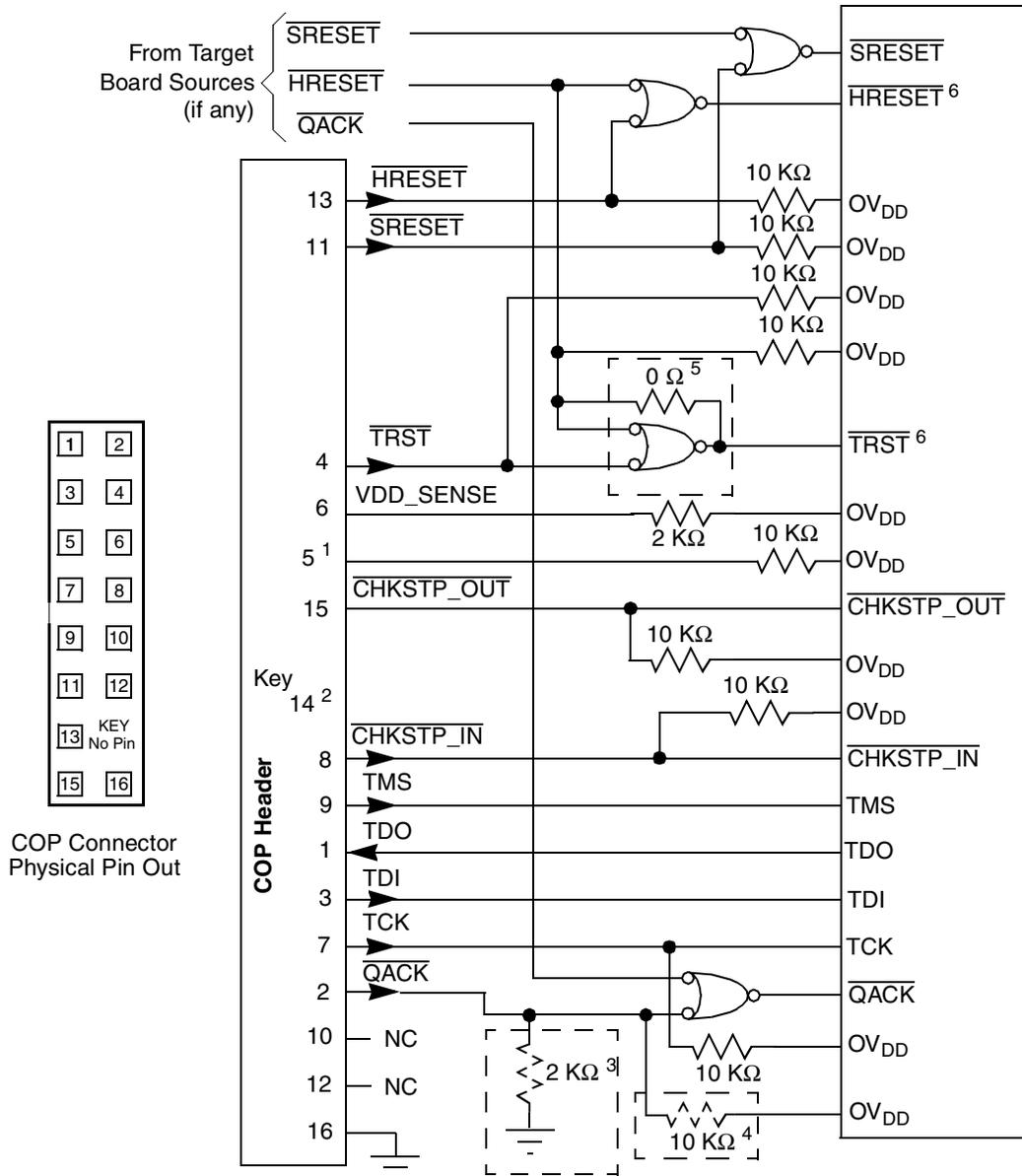


Figure 21. JTAG Interface Connection

9.7.1 Internal Package Conduction Resistance

For the exposed-die packaging technology described in Table 5, the intrinsic conduction thermal resistance paths are as follows:

- The die junction-to-case thermal resistance (the case is actually the top of the exposed silicon die)
- The die junction-to-board thermal resistance

Figure 24 depicts the primary heat transfer path for a package with an attached heat sink mounted to a printed-circuit board.

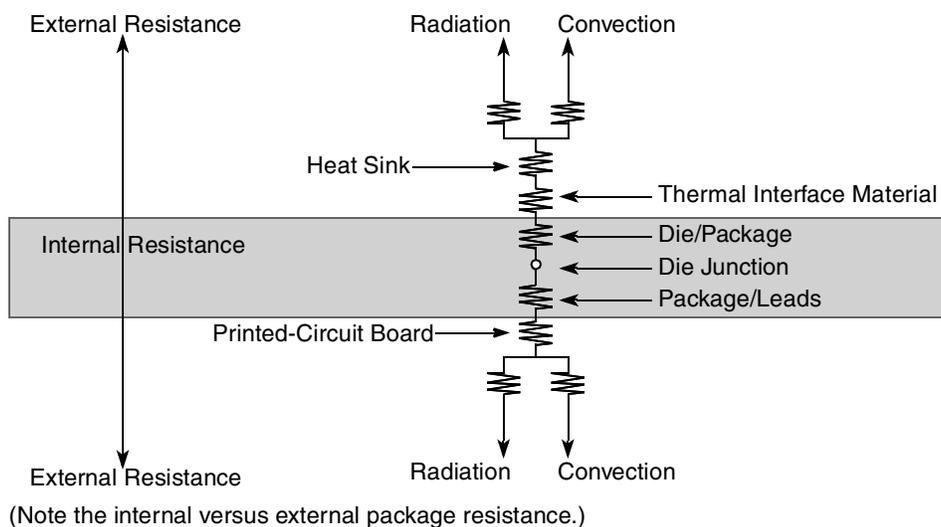


Figure 24. C4 Package with Heat Sink Mounted to a Printed-Circuit Board

Heat generated on the active side of the chip is conducted through the silicon, through the heat sink attach material (or thermal interface material), and, finally, to the heat sink, where it is removed by forced-air convection.

Because the silicon thermal resistance is quite small, the temperature drop in the silicon may be neglected for a first-order analysis. Thus, the thermal interface material and the heat sink conduction/convective thermal resistances are the dominant terms.

9.7.2 Thermal Interface Materials

A thermal interface material is recommended at the package lid-to-heat sink interface to minimize the thermal contact resistance. For those applications where the heat sink is attached by spring clip mechanism, Figure 25 shows the thermal performance of three thin-sheet thermal-interface materials (silicone, graphite/oil, fluoroether oil), a bare joint, and a joint with thermal grease as a function of contact pressure. As shown, the performance of these thermal interface materials improves with increasing contact pressure. The use of thermal grease significantly reduces the interface thermal resistance. That is, the bare joint results in a thermal resistance approximately seven times greater than the thermal grease joint.

Often, heat sinks are attached to the package by means of a spring clip to holes in the printed-circuit board (see Figure 22). Therefore, synthetic grease offers the best thermal performance due to the low interface pressure and is recommended due to the high power dissipation of the MPC7448. Of course, the selection

Due to the complexity and variety of system-level boundary conditions for today's microelectronic equipment, the combined effects of the heat transfer mechanisms (radiation, convection, and conduction) may vary widely. For these reasons, we recommend using conjugate heat transfer models for the board as well as system-level designs.

For system thermal modeling, the MPC7448 thermal model is shown in Figure 26. Four volumes represent this device. Two of the volumes, solder ball-air and substrate, are modeled using the package outline size of the package. The other two, die and bump-underfill, have the same size as the die. The silicon die should be modeled $8.0 \times 7.3 \times 0.86 \text{ mm}^3$ with the heat source applied as a uniform source at the bottom of the volume. The bump and underfill layer is modeled as $8.0 \times 7.3 \times 0.07 \text{ mm}^3$ collapsed in the z-direction with a thermal conductivity of $5.0 \text{ W}/(\text{m} \cdot \text{K})$ in the z-direction. The substrate volume is $25 \times 25 \times 1.14 \text{ mm}^3$ and has $9.9 \text{ W}/(\text{m} \cdot \text{K})$ isotropic conductivity in the xy-plane and $2.95 \text{ W}/(\text{m} \cdot \text{K})$ in the direction of the z-axis. The solder ball and air layer are modeled with the same horizontal dimensions as the substrate and is 0.8 mm thick. For the LGA package the solder and air layer is 0.1 mm thick, but the material properties are the same. It can also be modeled as a collapsed volume using orthotropic material properties: $0.034 \text{ W}/(\text{m} \cdot \text{K})$ in the xy-plane direction and $11.2 \text{ W}/(\text{m} \cdot \text{K})$ in the direction of the z-axis.

Conductivity	Value	Unit
Die ($8.0 \times 7.3 \times 0.86 \text{ mm}^3$)		
Silicon	Temperature-dependent	$\text{W}/(\text{m} \cdot \text{K})$
Bump and Underfill ($8.0 \times 7.3 \times 0.07 \text{ mm}^3$)		
k_z	5.0	$\text{W}/(\text{m} \cdot \text{K})$
Substrate ($25 \times 25 \times 1.14 \text{ mm}^3$)		
k_x	9.9	$\text{W}/(\text{m} \cdot \text{K})$
k_y	9.9	
k_z	2.95	
Solder Ball and Air ($25 \times 25 \times 0.8 \text{ mm}^3$)		
k_x	0.034	$\text{W}/(\text{m} \cdot \text{K})$
k_y	0.034	
k_z	11.2	

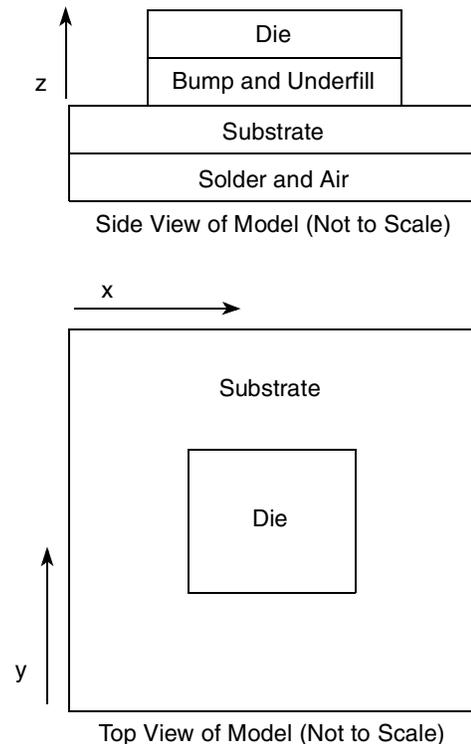


Figure 26. Recommended Thermal Model of MPC7448

9.7.4 Temperature Diode

The MPC7448 has a temperature diode on the microprocessor that can be used in conjunction with other system temperature monitoring devices (such as Analog Devices, ADT7461™). These devices use the negative temperature coefficient of a diode operated at a constant current to determine the temperature of the microprocessor and its environment. For proper operation, the monitoring device used should auto-calibrate the device by canceling out the V_{BE} variation of each MPC7448's internal diode.

The following are the specifications of the MPC7448 on-board temperature diode:

$$V_f > 0.40 \text{ V}$$

$$V_f < 0.90 \text{ V}$$

Operating range 2–300 μA

Diode leakage < 10 nA @ 125°C

Ideality factor over 5–150 μA at 60°C: $n = 1.0275 \pm 0.9\%$

Ideality factor is defined as the deviation from the ideal diode equation:

$$I_{fw} = I_s \left[e^{\frac{qV_f}{nKT}} - 1 \right]$$

Another useful equation is:

$$V_H - V_L = n \frac{KT}{q} \left[\ln \frac{I_H}{I_L} \right] - 1$$

Where:

I_{fw} = Forward current

I_s = Saturation current

V_d = Voltage at diode

V_f = Voltage forward biased

V_H = Diode voltage while I_H is flowing

V_L = Diode voltage while I_L is flowing

I_H = Larger diode bias current

I_L = Smaller diode bias current

q = Charge of electron (1.6×10^{-19} C)

n = Ideality factor (normally 1.0)

K = Boltzman's constant (1.38×10^{-23} Joules/K)

T = Temperature (Kelvins)

The ratio of I_H to I_L is usually selected to be 10:1. The previous equation simplifies to the following:

$$V_H - V_L = 1.986 \times 10^{-4} \times nT$$

Solving for T, the equation becomes:

$$nT = \frac{V_H - V_L}{1.986 \times 10^{-4}}$$

9.7.5 Dynamic Frequency Switching (DFS)

The DFS feature in the MPC7448 adds the ability to divide the processor-to-system bus ratio by two or four during normal functional operation. Divide-by-two mode is enabled by setting the HID1[DFS2] bit in software or by asserting the $\overline{\text{DFS2}}$ pin via hardware. The MPC7448 can be returned for full speed by clearing HID1[DFS2] or negating $\overline{\text{DFS2}}$. Similarly, divide-by-four mode is enabled by setting HID1[DFS4] in software or by asserting the $\overline{\text{DFS4}}$ pin. In all cases, the frequency change occurs in 1 clock cycle and no idle waiting period is required to switch between modes. Note that asserting either $\overline{\text{DFS2}}$ or $\overline{\text{DFS4}}$ overrides software control of DFS, and that asserting both $\overline{\text{DFS2}}$ and $\overline{\text{DFS4}}$ disables DFS completely, including software control. Additional information regarding DFS can be found in the *MPC7450 RISC Microprocessor Family Reference Manual*. Note that minimum core frequency requirements must be observed when enabling DFS, and the resulting core frequency must meet the requirements for $f_{\text{core_DFS}}$ given in [Table 8](#).

9.7.5.1 Power Consumption with DFS Enabled

Power consumption with DFS enabled can be approximated using the following formula:

$$P_{\text{DFS}} = \left[\frac{f_{\text{DFS}}}{f} (P - P_{\text{DS}}) \right] + P_{\text{DS}}$$

Where:

P_{DFS} = Power consumption with DFS enabled

f_{DFS} = Core frequency with DFS enabled

f = Core frequency prior to enabling DFS

P = Power consumption prior to enabling DFS (see [Table 7](#))

P_{DS} = Deep sleep mode power consumption (see [Table 7](#))

The above is an approximation only. Power consumption with DFS enabled is not tested or guaranteed.

9.7.5.2 Bus-to-Core Multiplier Constraints with DFS

DFS is not available for all bus-to-core multipliers as configured by PLL_CFG[0:5] during hard reset. The complete listing is shown in [Table 16](#). Shaded cells represent DFS modes that are not available for a particular PLL_CFG[0:5] setting. Should software or hardware attempt to transition to a multiplier that is not supported, the device will remain at its current multiplier. For example, if a transition from DFS-disabled to an unsupported divide-by-2 or divide-by-4 setting is attempted, the bus-to-core multiplier will remain at the setting configured by the PLL_CFG[0:5] pins. In the case of an attempted transition from a supported divide-by-2 mode to an unsupported divide-by-4 mode, the device will remain in divide-by-2 mode. In all cases, the HID1[PC0-5] bits will correctly reflect the current bus-to-core frequency multiplier.

11.2 Part Numbers Not Fully Addressed by This Document

Parts with application modifiers or revision levels not fully addressed in this specification document are described in separate hardware specification addenda which supplement and supersede this document. As such parts are released, these specifications will be listed in this section.

Table 19. Part Numbers Addressed by MC7448xxnnnnNx Series Hardware Specification Addendum (Document Order No. MPC7448ECS01AD)

xx	7448	xx	nnnn	N	x
Product Code	Part Identifier	Package	Processor Frequency	Application Modifier	Revision Level
MC	7448	HX = HCTE BGA VS = RoHS LGA VU = RoHS BGA	1400	N: 1.15 V ± 50 mV 0 to 105 °C (date code 0613 and later) ²	C: 2.1; PVR = 0x8004_0201 D: 2.2; PVR = 0x8004_0202
MC PPC ¹			1400	N: 1.1 V ± 50 mV 0 to 105 °C (date code 0612 and prior) ²	
MC PPC ¹			1267 Revision C only	N: 1.1 V ± 50 mV 0 to 105 °C	
MC PPC ¹			1267 Revision D only	N: 1.05 V ± 50 mV 0 to 105 °C	
MC PPC ¹			1250	N: 1.1 V ± 50 mV 0 to 105 °C	
MC PPC ¹			1000 867 800 667 600	N: 1.0 V ± 50 mV 0 to 105 °C	

Notes:

1. The P prefix in a Freescale part number designates a “Pilot Production Prototype” as defined by Freescale SOP 3-13. These parts have only preliminary reliability and characterization data. Before pilot production prototypes can be shipped, written authorization from the customer must be on file in the applicable sales office acknowledging the qualification status and the fact that product changes may still occur as pilot production prototypes are shipped.
2. Core voltage for 1400 MHz devices currently in production (date code of 0613 and later) is 1.15 V ± 50 mV; all such devices have the MC product code. The 1400 MHz devices with date code of 0612 and prior specified core voltage of 1.1 V ± 50 mV; this includes all 1400 MHz devices with the PPC product code. See [Section 11.3, “Part Marking,”](#) for information on part marking.